

FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))Attorney Docket No.: P2001,0176
Appl. No.:

Applicant: JOHANNES BAUR ET AL.

Filing Date: September 9, 2003
Group Art Unit:

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
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	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES / NO
<i>SM</i>	J	01/93310 A2	12/6/01	WIPO			
	K	01/61765 A1	8/23/01	WIPO			
	L	2 271 087 A	4/6/94	U.K.			
	M	0 611 131 A1	8/17/94	Europe			
<i>SM</i>	N	0 405 757 A2	1/2/91	Europe			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>Samantha</i>	DATE CONSIDERED <i>3/11/04</i>

FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

Attorney Docket No.:

P2001,0176

Applic. No.

10/657,841

Applicant

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J	61 110 476	05/28/86	Japan			X
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	J. Zhang et al.: "Precise microfabrication of wide band gap semiconductors (SiC and GaN) by VUV-UV multiwavelength laser ablation", <i>Applied Surface Science</i> , Vol. 127-129, 1998, pp. 793-799
	P	W. N. Carr: "Photometric Figures Of Merit For Semiconductor Luminescent Sources Operating in Spontaneous Mode", <i>Infrared Physics</i> , 1966, Vol. 6, pp. 1-19

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

